





## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R A	Junction-to-Ambient		90	/W

# **Electrical Characterizes** @T<sub>A</sub>=25 unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	20			V	$V_{GS} = 0V, I_D$
В	Static Drain-to-Source on-resistance		18	22	m	V <sub>GS</sub> =4.5V, I <sub>D</sub> =6.5A
$R_{DS(on)}$			24	30	m	V <sub>GS</sub> =2.5V, I <sub>D</sub> =5.5A
V <sub>GS(th)</sub>	Gate threshold voltage	0.4		1	V	$V_{DS} = V_{GS}, I_{D}$
I <sub>DSS</sub>	Drain-to-Source leakage current			1		V <sub>DS</sub> =20V,V <sub>GS</sub> =0V
1	Cata ta Sauraa faruard laakara			±1		V <sub>GS</sub> =±4.5V,V <sub>DS</sub> =0V
$I_{GSS}$	Gate-to-Source forward leakage			±10	uA	V <sub>GS</sub> =±8V,V <sub>DS</sub> =0V
Qg	Total gate charge		10			V <sub>DS</sub> =10V
Q <sub>gs</sub>	Gate-to-Source charge		2.3		nC	I <sub>D</sub> =6.5A
$Q_{gd}$	Gate-to-Drain("Miller") charge		3			V <sub>GS</sub> =4.5V
t <sub>d(on)</sub>	Turn-on delay time		6.5			V <sub>DD</sub> =10V
t <sub>r</sub>	Rise time		13			I <sub>D</sub> =1A
t <sub>d(off)</sub>	Turn-Off delay time		50		ns	V <sub>GS</sub> =5V
t <sub>f</sub>	Fall time		30			R <sub>GEN</sub>
C <sub>iss</sub>	Input capacitance		1160			V <sub>GS</sub> = 0V
Coss	Output capacitance		200		pF	V <sub>DS</sub> = 10V
C <sub>rss</sub>	Reverse transfer capacitance		140			1MHz

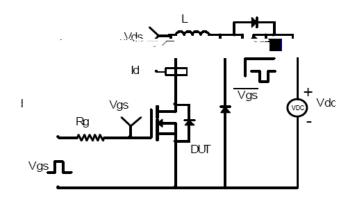
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	0.5		٨	MOSFET symbol	
	(Body Diode)			6.5	А	

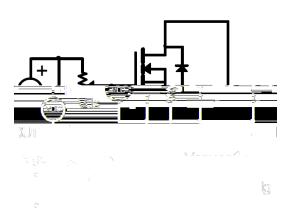


## **Test Circuits and Waveforms**

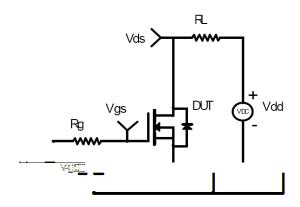
#### **EAS Test Circuit:**



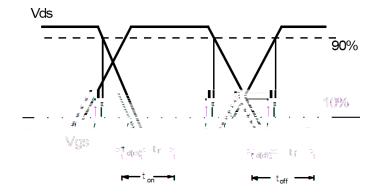
### **Gate Charge Test Circuit:**



### **Switching Time Test Circuit:**



#### **Switching Waveforms:**



## **Notes:**

Calculated continuous current based on maximum allowable junction temperature.

Repetitive rating; pulse width limited by max. junction temperature.

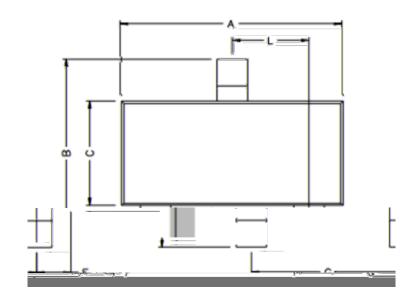
The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.

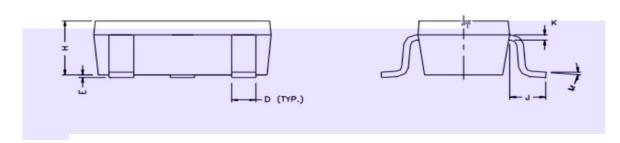
The value of R  $_{\rm A}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25



# **Mechanical Data**

## SOT-23 Package Outline(Unit:mm)





Γ	REF.	Millimeter		REF.	Millimete	
	KEF.	Min.	Max.	KEF.	Min.	Max.
	Α	2.80	3.00	G	1.80	2.00
Г	4	2.30	2.50	H	0.90	1.1
	C	1.20	1.40	K	0.10	0.20
	D	0.30	0.50	J	0.35	0.70
	Е	0	0.10	L	0.92	0.98
	F	0.45	0.55	М	0°	10°





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